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UTILITY PATENT APPLICATION FOR:

OPTIMIZATION OF CLOCK SCHEDULING FOR A

SYNCHRONOUS SYSTEM

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1 **OPTIMIZATION OF CLOCK SCHEDULING FOR A SYNCHRONOUS SYSTEM**

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3 FIELD OF THE INVENTION

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5   This invention relates generally to synchronous digital circuitry such as that used in

6 computers and digital processing systems, and more particularly to synchronization of clock

7 or timing signals using delay.

8

9 BACKGROUND OF THE INVENTION

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11   Synchronous (i.e., clocked or pulsed) circuits must operate within timing constraints.

12 Synchronous logic circuits typically include a clock distribution network for providing a clock

13 signal to various sub-circuits. A typical clock network includes one or more clock sources

14 that are coupled to a number of clock "sinks." A clock sink is any circuit or set of circuits

15 accepting a clock input. In their simplest form, clock sinks are flip-flops and latches.

16 Examples of more sophisticated sinks, involving several flip-flops or latches in the same time

17 domain, include registers, counters, and state machines.

18

19   Figure 1 illustrates clock distribution throughout parts of a synchronous logic circuit

20 100. The circuit 100 may be a VLSI (very large scale integration) integrated circuit, such as a

21 microprocessor.   The circuit 100 comprises a clock 110 and several clock sinks 120

22 connected to the clock 110 by clock lines (also called traces) 130. The circuit 100 also

23 comprises logic circuits (not shown) interconnecting the sinks 120. The physical path lengths

24 along the clock lines 130 to each sink 120 are generally different. Because of the non-

25 uniform lengths of clock lines and other factors such as trace resistance, trace capacitance and

26 load capacitance, clock pulses generally arrive at each sink 120 at different times. In other

27 words, the clock signals are generally out of phase when they arrive at the sinks 120. A

28 measure of this phase mismatch or non-uniformity in clock arrival time is "clock skew." The

29 skew between a clock signal at two points is the time delay or phase difference between the

30 clock signals at those two points. In the circuit 100 having several clock sinks 120, maximum

1 clock skew between any two sinks 120 is usually specified as some percentage (e.g., 10%) of

2 the clock period.

3

4   Excessive clock skew is undesirable. If clock skew is too great, then the sinks 120

5 may fail to operate together properly. If a clock signal arrives at a sink 120 too early or too

6 late relative to other events, then the circuit 100 may experience race conditions. Another

7 negative consequence is that clock skew can be a limiting factor in how fast the clock 110 can

8 operate. Misoperation and clock speed limitations result from violations of a setup or hold

9 time of a sink 120.

10

11   Figure 2 illustrates setup and hold times for the case where the sink is a latch. Figure

12 2A shows a dynamic latch 200 accepting an input D and a clock signal CLK. The dynamic

13 latch 200 produces an output Q, which follows the input D, after a small delay, when the

14 clock signal CLK is high and remains in the same state when the clock signal CLK is low.

15 Figure 2B shows waveforms of the clock signal CLK, the input D and the output Q. As

16 shown in Figure 2B, the input D pulses high briefly. In order for the output Q to follow the

17 input D, the input pulse must be high for a setup time T_S before the clock signal CLK falls

18 low and stay high for a hold time T_H after the clock signal CLK falls low. The setup time T_S

19 or the hold time T_H may be violated if the clock signal CLK drifts, as can happen when there

20 is excessive clock skew.

21

22   In the prior art, there are several approaches for minimizing clock skew. One

23 approach is "retiming," typified by U.S. Patent 5,849,610. Retiming is physical placement of

24 sinks and re-routing of clock lines to equalize path length. However, perfect distance

25 equalization is seldom possible. Other design considerations often mandate sink and trace

26 placement. Furthermore, physical distance is only one factor affecting propagation delay.

27

28   Another approach is the method of U.S. Patent 6,075,832, which discloses variable

29 delay elements on clock lines. The delay amounts are controlled by feedback control using a

30 delay locked loop that dynamically equalizes delay during circuit operation. A disadvantage

1   of this method is that it is complex, requiring extra space and power in the circuit.

2

3   Yet another approach is "clock scheduling," such as disclosed in its most elementary

4   form in U.S. Patent 5,758,130. According to that patent, a delay is introduced along a shorter

5   clock trace so as to synchronize its arrival with that of a longer clock trace. More generally,

6   clock scheduling involves delaying clock signals before the clock inputs to various sinks, so

7   that the clock signals arrive at their destination sinks at the same time (zero skew scheduling)

8   or in some other desired relationship with each other (non-zero clock skew scheduling). Ivan

9   S. Kourtney and Eby G. Friedman, "Timing Optimization through Clock Skew Scheduling,"

10   Kluwer Academic Publishers, 2000 (ISBN 0-7923-7796-6), which is hereby incorporated by

11   reference, discusses non-zero clock scheduling problem in great detail and discloses solutions

12   based on linear programming and quadratic programming. Unfortunately, both techniques,

13   which are entirely deterministic, do not always converge to a solution to this problem.

14

15   SUMMARY OF THE INVENTION

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17   In one respect, the invention is a method for determining a plurality of clock delay

18   values. Each delay value is associated with a delay element on a clock line leading to a clock

19   sink in a synchronous circuit. The method determines an initial set of delay values and

20   executes an optimization algorithm, beginning with the initial set of delay values, to arrive at

21   a set of delay values that at least approximately meet a criteria while satisfying timing

22   constraints associated with selected pairs of logically connected clock sinks. The

23   optimization algorithm randomly modifies the set of delay values. In one embodiment, the

24   timing constraints are defined in terms of setup and hold times. In preferred forms, the

25   optimization algorithm is a genetic algorithm or a gradient descent algorithm.

26

27   In another respect, the invention is an synchronous logic circuit having delay elements

28   determined by the above method.

29

1   In yet another respect, the invention is a computer readable medium on which is
2   embedded computer software that performs the above method.

3

4   In comparison to known prior art, certain embodiments of the invention are capable of
5   achieving certain advantages, including some or all of the following: (1) the algorithms are
6   capable of converging when other solutions do not; (2) the algorithms are capable of
7   converging to a better solution than prior art solutions; (3) the algorithms converge more
8   quickly than other solutions; and (4) the algorithms are adaptable to variations from device to
9   devices. Those skilled in the art will appreciate these and other advantages and benefits of
10   various embodiments of the invention upon reading the following detailed description of a
11   preferred embodiment with reference to the below-listed drawings.

12

13   BRIEF DESCRIPTION OF THE DRAWINGS

14

15   Figure 1 is a diagram illustrating clock distribution throughout parts of a synchronous
16   logic circuit;
17   Figure 2 illustrates setup and hold times during a pulse of a clock signal;
18   Figure 3 is a block diagram illustrating clock distribution throughout parts of a
19   synchronous logic circuit, according to an embodiment of the invention;
20   Figure 4 is a diagram illustrating a configuration of tuned delay elements used for
21   clock distribution along a local datapath, according to one embodiment of the invention; and
22   Figures 5-7 are flowcharts of timing optimization algorithms, according to
23   embodiments of the invention.

24

25   DETAILED DESCRIPTION OF A PREFERRED EMBODIMENT

26

27   Figure 3 is a block diagram illustrating clock distribution throughout parts of a
28   synchronous logic circuit 300, according to an embodiment of the invention. Like the circuit
29   100, the circuit 300 comprises a clock 110 and several clock sinks 120 connected to the clock
30   110 by clock lines 130. Unlike the circuit 100, the circuit 300 also comprises delay elements

1 340 connected before each sink 120. Although Figure 3 shows one delay element 340 for

2 each sink 120, a delay element 340 can feed multiple sinks, or some sinks may not have delay

3 elements on their clock inputs. The delay elements 340 can be buffers, series circuits of an

4 even number of inverters or any other means for delaying a signal known to those skilled in

5 the art. The delay elements 340 are adjustable either dynamically during operation of the

6 circuit 300 or statically during manufacture or initial configuration of the circuit 300.

7 Preferably, a delay element 340 is constructed as a series of even number of inverts, every

8 second output of which is input to a multiplexer, whose select lines are used to control which

9 output and thus how much delay is provided. Alternate structures for the delay elements 340

10 include delay locked loops and a series of inverters having controllable power supply

11 voltages. Regardless of the structure of the delay elements 340, techniques for selecting the

12 set of delay values for the delay elements 340 is described in detail below.

13

14 Figure 3 also illustrates a logic circuit 350 interconnecting some of the sinks 120.

15 Many other logic circuits are likely present in the circuit 300, but only one is illustrated for

16 clarity. The logic circuit 350 operates on data flowing from sink(s) to sink(s). Two sinks 120

17 and the logic circuit 350 interconnecting them form a local datapath. The circuit 300, if

18 typical of most logic systems, contains a large number of local datapaths.

19

20 Figure 4 illustrates a local datapath in greater detail, for the case where the sinks are

21 latches. The local datapath begins at a latch 400_i, where a signal D_i is input and a signal Q_i is

22 output. The signal Q_i is input to the logic circuit 350, which outputs a signal D_j. A latch 400_j

23 accepts as input the signal D_j and outputs a signal Q_j. A clock signal CLK is also supplied to

24 the latches 400i and 400j. The clock signal CLK going to the latch 400_i has a skew C_i relative

25 to some reference. The clock signal CLK going to the latch 400_j has a skew C_j relative to the

26 same reference. Delay elements 340_i and 340_j introduce additional delay in the clock signal

27 CLK before reaching the latches 400_i and 400_j, respectively. The delay values for the delay

28 elements 340_i and 340_j are chosen to satisfy the setup and hold time constraints of the latches

29 400_i and 400_j, as will be explained next.

30

Assume multiple paths traverse across the logic circuit 350. Denote the longest propagation delay of these paths as D_{ijL}, and the shortest as D_{ijS}. Then the setup and hold time constraints are given by the following inequalities:

$$T_{Si} + C_i + G_i + D_{ijL} < T_{CLK+} + C_j + G_j \qquad (1)$$

$$C_i + G_i + D_{ijS} > C_j + G_j + T_{Hj} \qquad (2)$$

where T_{CLK+} is the nominal duration of a positive pulse on the clock signal CLK, assuming that the latches activate upon a positive clock pulse, and T_{Si} and T_{Hj} are the setup and hold times for the latches 400i and 400j, respectively. As a simplification, which is often true, the setup times and hold times for each latch may be assumed to be the same, in which case the i and j subscripts can be dropped from T_{Si} and T_{Hj}.

As an alternative, the constraint inequalities (1) and (2) can be modified to include a safety margin, SM, as follows:

$$T_{Si} + C_i + G_i + D_{ijL} + SM < T_{CLK+} + C_j + G_j \qquad (3)$$

$$C_i + G_i + D_{ijS} - SM > C_j + G_j + T_{Hj} \qquad (4)$$

Including SM can result in a solution that is less sensitive to operating variations, such as might arise from voltage or temperature variations. However, including SM can also constrain the solution space such that a less optimal solution results.

The inequalities (1)-(4) are illustrative, and not limiting, examples of timing constraints between two sinks connected by logic. The inequalities (1)-(4) are appropriate for the latches 400i and 400j, which are edge-triggered as shown in Figure 2B. Similar inequalities can be stated for latches triggered on the opposite clock edge, or for level-triggered sinks. Furthermore, other timing constraints involving other device and signal parameters are possible.

For a circuit containing N sinks, there are between order(N) and order(N^2) possible local datapaths. For each datapath there is a timing constraint, such as a pair of inequalities in the same form as (1) and (2) (or (3) and (4)), that must be satisfied. A solution to this set of inequalities is any set of delay values $\{G_k : 1 \leq k \leq N\}$ satisfying all the inequalities. The

1   solution space may be further constrained by the realizable limits of the delay values (e.g., -

2   128 ps (picoseconds) $\leq G_k \leq 128$ ps and/or only discrete values of G_k possible $\forall$ k). Although

3   there are potentially many solutions to this set of inequalities, a solution that is optimum or

4   nearly optimum in some sense is preferred. There are many possible criteria that define the

5   optimum, including, by way of illustration and not limitation, the following:

6                           $\min(T_{CLK+})$ (5)

7                           $\min(\sum G_k)$ or $\max(\sum G_k)$ (6)

8                           $\min[\sum(T_{skew}(i,j) - G_{ij})^2]$ (7)

9   In each case the criteria is minimization (or maximization) of some quantity, which is termed

10   the "objective function." The criteria in expression (5) is minimization of the clock signal's

11   positive pulse width and, indirectly, the clock period (i.e., maximization of clock frequency).

12   The objective function in expression (6) the total added delay, summed across all delay

13   elements G_k, $1 \leq k \leq N$. Note that maximization of $\sum G_k$, though not an intuitive thing to do, is

14   a valid criteria; note that because clock signals are periodic, a large delay is functionally

15   equivalent to a smaller delay modulo the clock period. The objective function in expression

16   (7) is the sum of squared norms of total skew $T_{skew}(i,j)$ from some target clock skew, G_{ij}, such

17   as a value in the middle of a permissible range, for all connected pairs i-j of delay elements.

18    $T_{skew}(i,j)$ may be defined as $G_i - G_j$ or $(C_i+G_i) - (C_j+G_j)$.

19

20   Given some optimization criteria, such as those in expressions (5)-(7), the problem is

21   to select delay values G_k, $1 \leq k \leq N$, within the solution space such that the optimization

22   criteria is met or approximately met. In other words, the problem is to determine the

23   optimum or approximately optimum solution, as defined by the given optimization criteria,

24   subject to the setup and hold time constraints (which define the solution space). Methods for

25   solving this problem are illustrated in Figures 5-7.

26

27   Figure 5 is a flowchart of a generalized timing optimization method 500. The method

28   500 comprises two steps: determining (510) an initial set of delay values and performing

29   (520) an optimization algorithm. The initial set of delay values may or may not be a solution,

30   i.e., they may or may not satisfy the constraints, such as, for example, the setup and hold time

1   inequalities (1) and (2). The optimization algorithm, which is preferably iterative, refines the

2   initial set of delay values so as to converge toward a solution that at least approximately

3   meets a given criteria. In other words, the optimization algorithm searches the space of

4   potential solutions to find a solution that is optimum or nearly optimum according to the

5   given criteria. The optimization algorithm operates with some randomness, rather than being

6   purely deterministic. As described below, the optimization algorithm is preferably a genetic

7   algorithm or a gradient descent algorithm; however, other optimization algorithms involving a

8   random component, such as simulated annealing or stochastic programming, are equally

9   possible.

10

11   In one form, the optimization algorithm is a genetic algorithm. Figure 6 is a flow

12   chart of a timing optimization method 600 based on a genetic algorithm. The method 600

13   begins by determining (610) a set of potential solutions. Each potential solution is an N-tuple

14   of delay values G_k, $1 \leq k \leq N$. The initial potential solutions are preferably random or

15   determined by a linear programming or quadratic programming algorithm, which are well-

16   known in the art but do not typically converge to the correct solution.

17

18   Next, the method 600 selects (620) parent potential solutions. Preferably, the

19   selecting step 620 is performed by conducting a tournament. In a preferred tournament, the

20   parents are selected randomly with probability proportional to their fitness values, which are

21   measures of how well the solutions meet the optimization criteria. For example, if the

22   optimization criteria is defined by $\min(\sum G_k)$, then potential solutions in the population are

23   assigned a selection probability inversely related to the quantity $\sum G_k$ for each potential

24   solution. Optionally, the function mapping from an objective function value to a fitness value

25   could involve scaling.

26

27   Next, the method 600 crosses-over (630). The crossing-over step 630 is a breeding or

28   mating step, to produce children potential solutions. In a preferred form, the crossing-over

29   step 630 produces two children from two parents. In the case where each delay value G_k is a

30   discrete variable, a potential solution may be represented as a concatenation of the binary

1   representations of each delay value: $G_1:G_2:...:G_N$. With both parents represented in this

2   manner, the crossing-over step 630 can be visualized by aligning a copy of one parent's bit

3   pattern above a copy of the other's. Next, the crossing-over step 630 divides the parents' bit

4   patterns into a number of regions. The number of regions and their endpoints are preferably

5   random. Then, the crossing-over step randomly swaps the bits within each region, region by

6   region independently. The resulting bit patterns are the two children. Each child has parts

7   (i.e., regions) of each parent (except the very rare case in which no swaps occur). The size,

8   number and locations of regions is arbitrary.

9

10   Next, the method 600 mutates (640) each delay value (G_k) in the children. The

11   preferred mutation is a Gaussian randomized mutation on a sink-by-sink basis. In this case,

12   the mutation step 640 adds to each delay value G_k in a child solution a Gaussian random

13   variable. Preferably, the Gaussian random variable is $N(0,\sigma)$ where 3σ is approximately one

14   clock period. In one embodiment, each delay value G_k is discrete and quantized to 6 bits (and

15   thus having 64 possible values) equally spaced from zero to one clock period, and the

16   Gaussian random variable is likewise rounded to truncated to the same resolution.

17

18   After the mutation step 640, the method 600 checks (650) whether the mutated

19   potential solution is a better than the previous one (before mutation). The checking step 650

20   evaluates the relevant objective function for potential solutions before and after mutation. If

21   the mutation is better, then the method 600 discards (660) the worst solutions from

22   consideration and iterates the steps 610-650, returning to the determining step 610 to

23   determine new potential solutions to replace the discarded ones. If the mutated potential

24   solution is not better, then the method 600 tests (670) whether the goal has been reached or

25   the maximum number of iterations have been performed. In either case, the method 600

26   terminates. The goal may be expressed as being within some tolerance of the ideal or a

27   desired solution.

28

29   Determination of which potential solutions are better or more fit preferably involves

30   both constraint satisfaction and meeting the optimization criteria. A true solution (i.e.,

1   satisfying the constraints) is better or more fit than a non-solution. Between two solutions,

2   the one that better meets the optimization criteria is better or more fit than the other.

3

4   Genetic algorithms, per se, are known. In the parlance of genetic algorithms, each

5   solution is a "chromosome," the whole set of potential solutions under consideration is a

6   "population" or "colony," and each iteration of the steps 610-660 is an "epoch" or

7   "generation." Those skilled in the art can vary the method 600 within the understanding of

8   genetic algorithms. For example, the size of the population is largely arbitrary, but a

9   population that is too small may take too long to converge while a population that is too large

10 may never drift towards any direction and therefore never converge.

11

12   In another form, the optimization algorithm is a gradient descent algorithm. Figure 7

13 is a flowchart of a timing optimization method 700 based on a gradient descent algorithm.

14 The method 700 begins by determining (710) initial delay values. The initial delay values are

15 preferably all-zero or determined by a linear programming or quadratic programming

16 algorithm. The method 700 next perturbs (720) the delay values. The perturbations are

17 preferably random steps that increase, decrease or hold unchanged each delay value.

18 Preferably, the perturbation is one of three effects: increase by a fixed amount, decrease by

19 the fixed amount or hold unchanged. In one embodiment, each delay value G_k is discrete and

20 quantized to a number of bits, the fixed amount is a single bit resolution. The method 700

21 next checks (730) whether the perturbed solution is better than the unperturbed solution. The

22 checking step 730 evaluates the relevant objective function for solutions before and after

23 perturbation. If the perturbed solution is not better, the method 700 discards it and returns

24 (740) to the last best solution before repeating the perturbation step 720. This loop continues

25 until a better solution is found, at which point, the method 700 can be said to be moving in

26 the right direction (or down the "gradient"). Thereafter, the method 700 continues to adjust

27 (750) the delay values in the same direction (i.e., for each delay value adjusting the amount by

28 which that delay value is increased or decreased). After each adjustment, the method 700

29 tests (760) whether the goal has been reached or the maximum number of iterations have been

30 performed. In either case, the method 700 terminates.

Gradient descent algorithms, per se, are known. Those skilled in the art can vary the method 700 within the understanding of gradient descent algorithms.

The methods 500, 600 and 700 are preferably applied to a synchronous circuit or system near the final steps in production. After manufacture of a batch of circuits, the circuit parameters, such as longest and short path delays, setup and hold times, and nominal clock skews can be measured for each device in the batch. Alternatively, these quantities can be analytically estimated for the entire batch before. However, manufacturing process variations can cause these parameters to differ from device to device. After measuring the pertinent parameters for a particular device, the methods 500, 600 or 700 can be used to determine the set of delay values to be programmed into the delay elements of the device. In this way, the methods 500, 600 and 700 are adaptable. Furthermore, the solutions attained by the methods 500, 600 and 700 are often less sensitive to operating variations, such as voltage and temperature variations, especially when a safety margin is included in the constraint equations or when the optimization criteria involves target skew values.

The methods 500, 600 and 700 can be applied to an entire clock scheduling problem wholly. Alternatively, multiple instances of methods 500, 600 and 700 can be run, each applied to a partition of the overall clock scheduling problem; then, the individual solutions can be patched together.

The methods 500, 600 and 700 can be performed by computer programs, which can exist in a variety of forms both active and inactive. For example, they can exist as software program(s) comprised of program instructions in source code, object code, executable code or other formats. Any of the above can be embodied on a computer readable medium, which include storage devices and signals, in compressed or uncompressed form. Exemplary computer readable storage devices include conventional computer system RAM (random access memory), ROM (read only memory), EPROM (erasable, programmable ROM), EEPROM (electrically erasable, programmable ROM), and magnetic or optical disks or tapes.

1 Exemplary computer readable signals, whether modulated using a carrier or not, are signals
2 that a computer system hosting or running the computer program can be configured to access,
3 including signals downloaded through the Internet or other networks. Concrete examples of
4 the foregoing include distribution of the programs on a CD ROM or via Internet download.
5 In a sense, the Internet itself, as an abstract entity, is a computer readable medium. The same
6 is true of computer networks in general.

7

8   What has been described and illustrated herein is a preferred embodiment of the
9 invention along with some of its variations. The terms, descriptions and figures used herein
10 are set forth by way of illustration only and are not meant as limitations. Those skilled in the
11 art will recognize that many variations are possible within the spirit and scope of the
12 invention, which is intended to be defined by the following claims -- and their equivalents --
13 in which all terms are meant in their broadest reasonable sense unless otherwise indicated.

14